



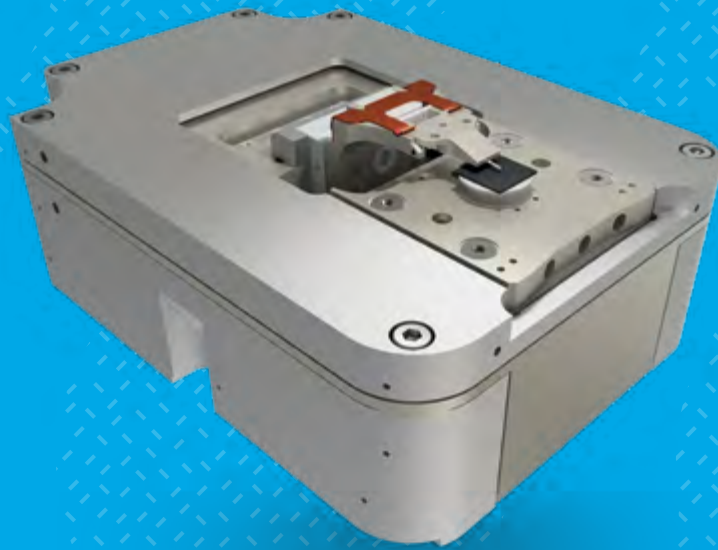
NenoVision

AFM Specially Designed for SEM

- Plug-and-play AFM solution for SEM microscopes
- Wide range of applications in the field of Materials Science and Nanotechnology, Semiconductor Industry, and Life Science
- Unique Correlative Microscopy Technique – CPEM
- Precise AFM tip navigation to the area of interest by SEM
- User-friendly and intuitive web-based interface

Explore Variety of Applications

- Characterization of nanostructures
- Graphene
- Nanowires
- Surface science
- Metal fatigue
- Crack propagations
- Solar cells analysis
- And many others...

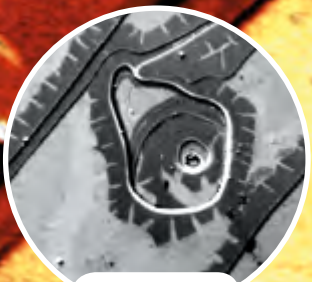


LiteScope™

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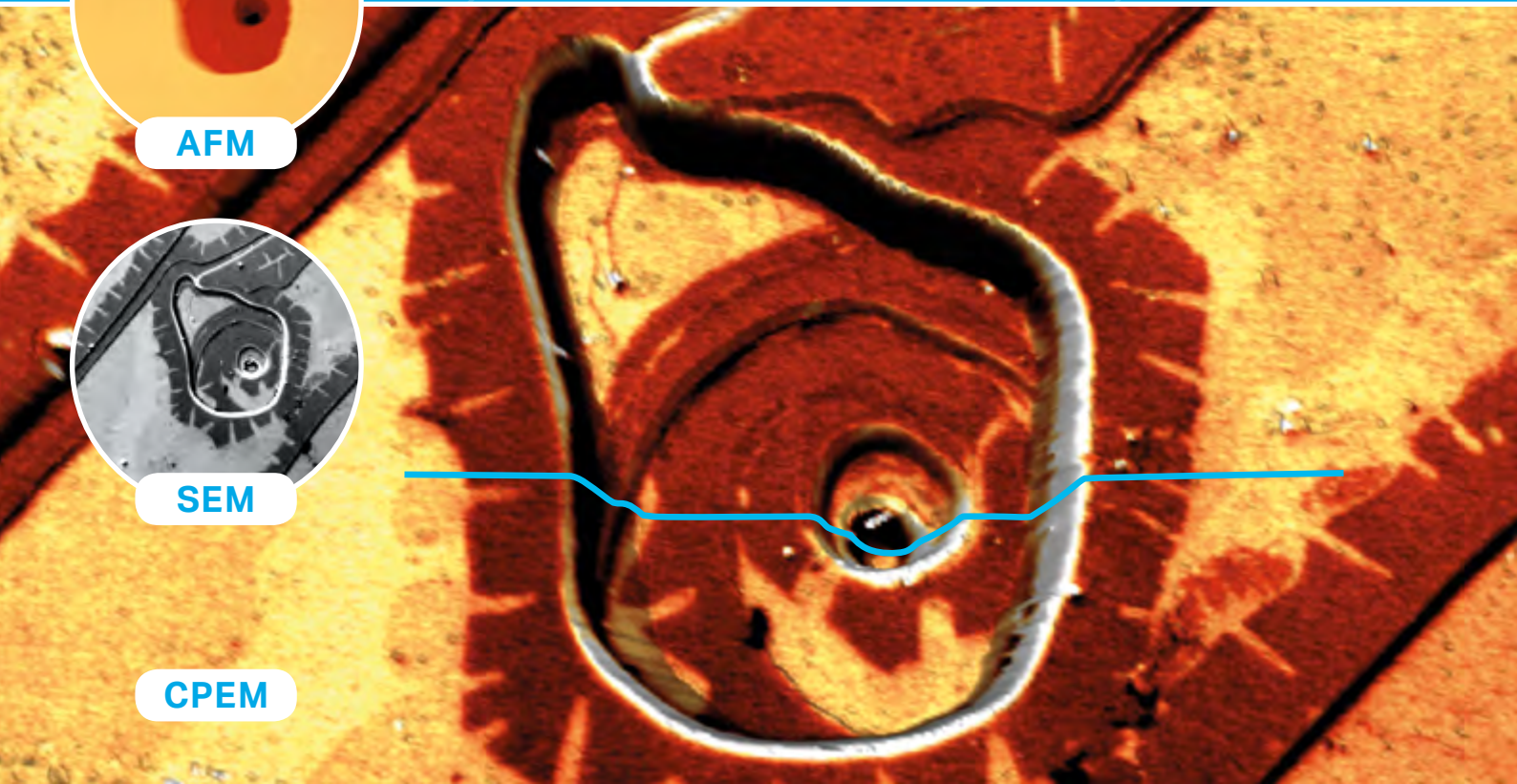


AFM



SEM

CPEM

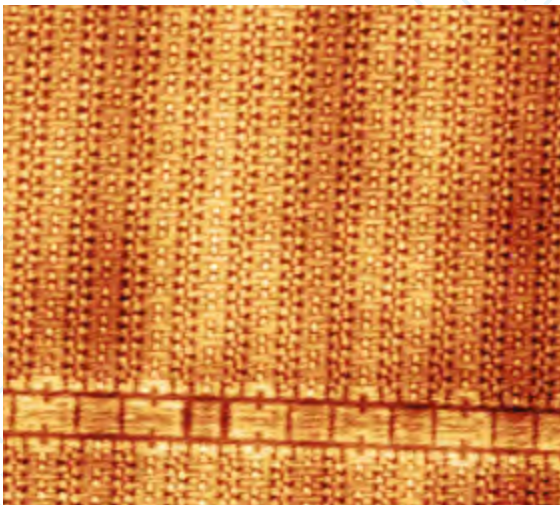




Applications

3D topography and depth profiling

The most natural application of AFM integrated into SEM is in-situ 3D topography measurement of selected structures. AFM provides precise height/depth profile measurement. ▶

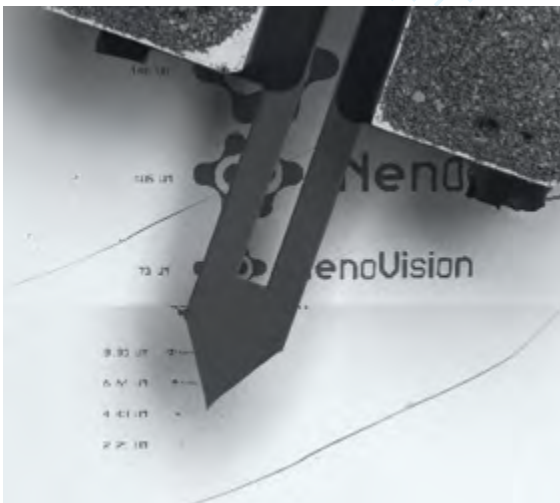
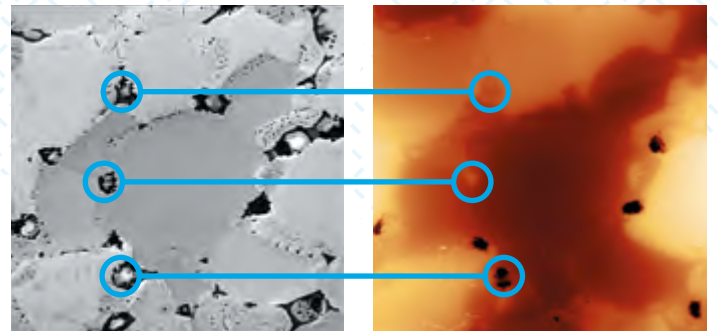


Roughness measurement

Integration of AFM directly into a FIB/SEM system allows in-situ analysis and surface roughness measurement (sub-nanometer RMS). AFM depth profiling enables FIB optimization and 3D surface characterization. ◀

Material vs. topography contrast

Correlative microscopy (SEM + AFM) instantly reveals material and topography contrasts, providing comprehensive information about your sample. ▶



Precise AFM tip navigation using SEM

Combination of SEM and AFM allows extremely precise and fast AFM tip navigation to a sub-micron area of interest. Applications can be found in localization and characterization of 1D, 2D, and 3D nanostructures, the semiconductor industry, life sciences, etc. ◀